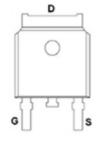
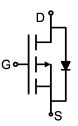


Main Product Characteristics:

V _{DSS}	-40V
R _{DS} (on)	24mohm(typ.)
I _D	-30A







TO-252

Marking and pin
Assignment

Schematic diagram

Features and Benefits:

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 100% Avalanche Rated



Preliminary Version: 1.0

page 1 of 6

Description:

It utilizes the latest trench processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications

Absolute max Rating:

Symbol	Parameter	Max.	Units	
I _D @ T _C = 25 °C	Continuous Drain Current, Vcs @ 10V	-30①		
I _D @ T _C = 100°C	I _D @ T _C = 100 ℃ Continuous Drain Current, V _{GS} @ 10V		Α	
I _{DM}	Pulsed Drain Current ②	-120		
D @TC = 25°C	Power Dissipation ③	83	W	
P _D @TC = 25°C	Linear Derating Factor	1.02	W/°C	
V _{DS}	Drain-Source Voltage	-40	V	
V _{GS}	Gate-to-Source Voltage	± 20	V	
Eas	Single Pulse Avalanche Energy @ L=0.3mH	93	mJ	
I _{AS}	Avalanche Current @ L=0.3mH	25	Α	
TJ	Operating Junction Temperature Range	-55 to + 150	°C	
T _{STG} Storage Temperature Range		-55 10 + 150		



Thermal Resistance

Symbol	Characterizes	Тур.	Max.	Units
Rejc	Junction-to-case ③	_	1.5	°C/W
D	Junction-to-ambient (t $ \leqslant 10 \mathrm{s}$) $ \oplus $	_	62	°C/W
R _{θJA}	Junction-to-Ambient (PCB mounted, steady-state) ④	_	40	°C/W

Electrical Characterizes $@T_A=25^{\circ}C$ unless otherwise specified

Symbol	Parameter		Тур.	Max.	Units	Conditions	
V _{(BR)DSS}	Drain-to-Source breakdown voltage	-40	_	_	V	V _{GS} = 0V, I _D =- 250μA	
Б	Static Praire to Course on registance	_	24	32	0	V _{GS} =-10V,I _D = -10A	
$R_{DS(on)}$	Static Drain-to-Source on-resistance	_	33	45	mΩ	V _{GS} =-4.5V,I _D = -6A	
V _{GS(th)}	Gate threshold voltage	-1	_	-3	V	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	
	Durin to Course leakens aument	_	_	-1		V _{DS} = -40V,V _{GS} = 0V	
I _{DSS}	Drain-to-Source leakage current	_	_	-50	μA	T _J = 125°C	
	Cata to Course forward lackers	_	_	100	^	V _{GS} =20V	
I _{GSS}	Gate-to-Source forward leakage	_	_	-100	nA	V _{GS} = -20V	
Qg	Total gate charge	_	26.2	_		I _D =- 10A,	
Q _{gs}	Gate-to-Source charge	_	7.2	_	nC	V _{DS} =-20V,	
Q _{gd}	Gate-to-Drain("Miller") charge	_	8.4	_		V _{GS} =- 10V	
t _{d(on)}	Turn-on delay time	_	15.9	_		V _{GS} =-10V, V _{DS} =-20V,	
tr	Rise time	_	49.0	_		$R_L=1\Omega$,	
t _{d(off)}	Turn-Off delay time	_	61.6	_	nS	R _{GEN} =3Ω	
t _f	Fall time	_	25.6	_		I _D =-20A	
C _{iss}	Input capacitance	_	1820	_		V _{GS} = 0V	
Coss	Output capacitance	_	248	_	pF	V _{DS} =-25V	
C _{rss}	Reverse transfer capacitance	_	162	_		f =1MHz	

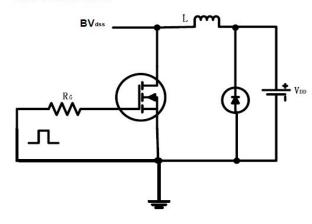
Source-Drain Ratings and Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
	Continuous Source Current (Body Diode)		_	-30①	А	MOSFET symbol
IS						showing the GHH ¥
	Pulsed Source Current		_	-120	А	integral reverse
I _{SM}	(Body Diode)	_				p-n junction diode.
V _{SD}	Diode Forward Voltage	_	-0.72	-1.2	V	I _S =-2.1A, V _{GS} =0V
t _{rr}	Reverse Recovery Time	_	30.8	_	nS	$T_J = 25 ^{\circ}\text{C}$, $I_F = -20\text{A}$, di/dt =
Qrr	Reverse Recovery Charge	_	31.1		nC	100A/µs

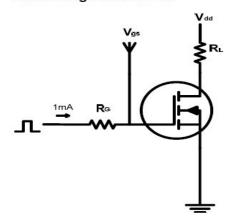


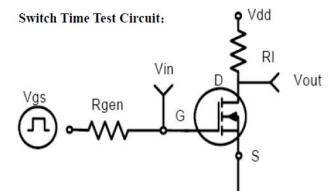
Test circuits and Waveforms

EAS test circuits:

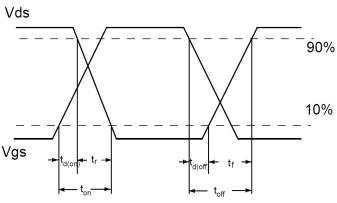


Gate charge test circuit:





Switch Waveforms:

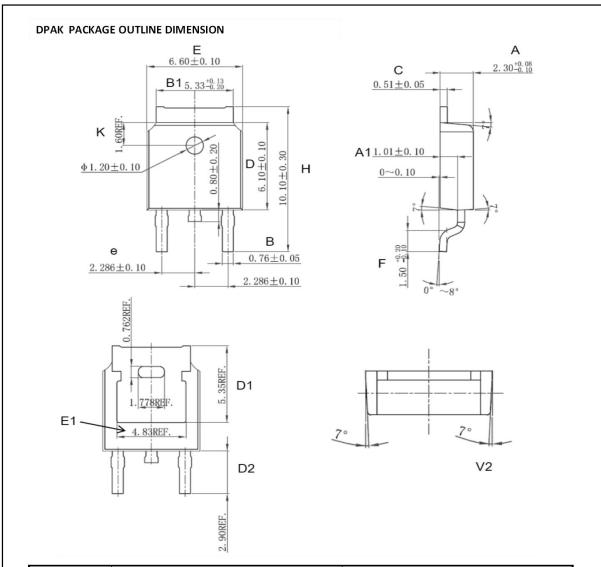


Notes:

- ①Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 75A.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- ⓐThe value of R_{θJA} is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25 $^{\circ}$ C.
- ⑤These curves are based on the junction-to-case thermal impedence which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of T_{J(MAX)}=175℃.



Mechanical Data:



Symbol	Dimension In Millimeters			Dimension In Inches		
Зуньон	Min	Nom	Max	Min	Nom	Max
Α	2.200	2.300	2.380	0.087	0.091	0.094
A1	0.910	1.010	1.110	0.036	0.040	0.044
В	0.710	0.760	0.810	0.028	0.030	0.032
B1	5.130	5.330	5.460	0.202	0.210	0.215
С	0.460	0.510	0.560	0.018	0.020	0.022
D	6.000	6.100	6.200	0.236	0.240	0.244
D1		5.350 (REF)		0.211 (REF)		
D2		2.900 (REF)		0.114 (REF)		
Е	6.500	6.600	6.700	0.256	0.260	0.264
E1	4.83 (REF) 0.190 (REF)					
e	2.186	2.286	2.386	0.086	0.090	0.094
Н	9.800	10.100	10.400	0.386	0.398	0.409
F	1.400	1.500	1.700	0.055	0.059	0.067
K	1.600 (REF)				0.063 (REF)	
V2		8º (REF)			8º (REF)	



Ordering and Marking Information

Device Marking: SSF4031C1

Package (Available)
DPAK (TO-252)
Operating Temperature Range

C : -55 to 150 ℃

Devices per Unit

Option1:

Package Type	Units/Tape	Tapes/Inner Box	Units/Inner Box	Inner Boxes/Carton	Units/Carton Box
				Box	
TO-252	2500	2	5000	7	35000

Option2:

Package	Units/Tape	Tapes/Inner	Units/Inner	Inner	Units/Carton
Type		Box	Box	Boxes/Carton	Box
				Box	
TO-252	2500	1	2500	10	25000

Reliability Test Program

Test Item	Conditions	Duration	Sample Size
High	T _j =125℃ to 150℃ @	168 hours	3 lots x 77 devices
Temperature	80% of Max	500 hours	
Reverse	V _{DSS} /V _{CES} /VR	1000 hours	
Bias(HTRB)			
High	T _j =150℃	168 hours	3 lots x 77 devices
Temperature	@ 100% of Max V _{GSS}	500 hours	
Gate		1000 hours	
Bias(HTGB)			



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